Two models of imperfect delayed repair in a continuously monitored system and subject to a continuous deterioration

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Condition-Based maintenance

- Condition-Based Maintenance (CBM) is a maintenance program that recommends to perform maintenance actions based on the information collected through condition monitoring
- CBM attempts to avoid unnecessary maintenance tasks by performing maintenance actions only when there is evidence of abnormal behaviour of the system
- A CBM program properly implemented can significantly reduce the total maintenance costs

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Imperfect maintenance

- Under a CBM program, based on the information data, different maintenance actions are programmed
- After a maintenance action, system condition depends on the maintenance efficiency. Two extreme cases
 - Minimal maintenance: system condition is just the same as before (ABAO)
 - Perfect maintenance: system condition is the same as if it were new (AGAN)

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- Reality lies between these two extreme cases: Imperfect maintenance
- Imperfect maintenance has been widely investigated in the literature.
 However, its implementation in CBM is limited

General framework

- A deteriorating system
- Continuous monitoring
- Delay time for the maintenance team arrival
- Imperfect repair performed by the maintenance team
- Maintenance strategy based on the system condition

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General Assumptions

- System subject to a continuous degradation and continuously monitored
- System failure, maintenance team is called for repairing the broken system
- The maintenance team takes a fixed amount of time to start the repair ("delayed repair") and the system is unavailable. This repair is instantaneous
- Maintenance strategy: reduce the system downtime. The maintenance team is called to perform a maintenance action before the system failure. It takes a fixed time to start the maintenance action
 - If the system is failed at maintenance action time: corrective replacement
 - If the system is working at maintenance action time: imperfect repair based on
 - System degradation reduction (First Maintenance Model)
 - System age reduction (Second Maintenance Model)

Formulation of the problem

General situation

The degradation is modelled by a gamma process (X_t)_{t≥0} where X_t is distributed Gamma (αt, β) with density

$$f_t(x) = \frac{\beta^{\alpha t}}{\Gamma(\alpha t)} x^{\alpha t-1} e^{-\beta x}, \ x \ge 0, \ \alpha > 0, \beta > 0.$$

 F_t and \overline{F}_t cumulative distribution and survival function of X_t .

The system fails when its degradation exceeds the level L,

$$\sigma_L = \inf(t > 0: X_t > L).$$

- At time σ_L, a signal is sent to the maintenance team which arrives at time σ_L + τ and replaces the system by a new one.
- The system is unavailable from σ_L up to $\sigma_L + \tau$.

Maintenance strategy

Preventive maintenance strategy

- Signal sent to the maintenance team when the system degradation reaches M (0<M<L) (at time σ_M).
- At $\sigma_M + \tau$, the maintenance actions start
 - If the system is failed, a corrective replacement is performed
 - ▶ If $\sigma_M + \tau < \sigma_L$, a preventive imperfect repair is performed. After repair
 - ▶ If system degradation greater *M*, preventive replacement
 - If system degradation less M, goes on working

Maintenance actions

- Corrective replacement (CR): system is broken at team maintenance arrival
- Preventive repair (PM): repair brings the deterioration below M
- Preventive repair plus a preventive replacement (PM+PR): repair does not bring deterioration below M

First Model

Preventive repair (imperfect)

- First model: Repair removes a part (ρ%) of the degradation accumulated from the last maintenance action (0 ≤ ρ ≤ 1)
- Second model: Repair removes a part (ρ%) of the age accumulated from the last maintenance action (0 ≤ ρ ≤ 1)

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Goals

- Derive Markov renewal type equations for some transient measures
 - Transient Reliability
 - Transient Availability
 - Transient Expected Cost

Comparison the two models of repair

Maintained system evolution

 $S_1 = U_1 = \sigma_M^{(1)} + au$ 1st maintenance action time, Y_t maintained system evolution

- If $X_{S_1}^{(1)} > L$ CR at S_1 , $Y_{S_1} = 0$
- If X⁽¹⁾_{S1} ≤ L preventive repair (PM) at S₁, reduction of the ρ% of the degradation

•
$$(1 - \rho)X_{S_1} \ge M$$
, unmaintainable system $Y_{S_1} = 0$

•
$$(1-\rho)X_{S_1} < M, \ Y_{S_1} = (1-\rho)X_{S_1}$$

From Y_{S_1} , 2nd maintenance action is planned at $S_2 = S_1 + \sigma_{M-Y_{S_1}}^{(2)} + \tau = S_1 + U_2$ If $Y_{S_2}^- > L$ CR at S_2 , $Y_{S_2} = 0$ If $X_{-}^- \leq I$ PM at S_2 reduction of the ρ_{M}^{0} of the σ_{M}^{0} of the $\sigma_{$

If X⁻_{S₂} ≤ L PM at S₂, reduction of the ρ% of the degradation accumulated in U₂

►
$$Y_{S_1} + (1 - \rho)X_{U_2}^{(2)} \ge M$$
, unmaintainable system $Y_{S_2} = 0$
► $Y_{S_1} + (1 - \rho)X_{U_2}^{(2)} < M$, $Y_{S_2} = Y_{S_1} + (1 - \rho)X_{U_1}^{(2)}$



After S_n , evolution of $(Y_t)_{t>S_n}$ depends on $(Y_t)_{t\leq S_n}$ only through Y_{S_n} , (Y_t) semi-regenerative process with underlying MRP (S_n, Y_n) where $Y_n = Y_{S_n}$ and interarrival times $U'_n s$

$$(S_1, Y_{S_1}^-) = (\sigma_M + \tau, X_{\sigma_M + \tau}) \stackrel{\mathcal{L}}{=} (\sigma_M, X_{\sigma_M}) + (\tau, X_{\tau}^{(1)}).$$

 $X_{ au}^{(1)}$ independent copy of $X_{ au}$

Probability distribution function of (σ_M, X_{σ_M}) , Bertoin (1998)

$$f_{(\sigma_M, X_{\sigma_M})}(t, y) = \int_{s=0}^{\infty} \mathbf{1}_{\{M \le y < M+s\}} f_t(y-s) \mu(ds),$$

 $\mu(ds)$ Gamma process Levy measure $\mu(ds) = \alpha e^{-eta s}/s$

Probability distribution function of $(S_1, Y_{S_1}^-)$

For $s > \tau$ and x > M

$$h^{M}(s,x) = \iint_{\mathbb{R}^{2}_{+}} \mathbf{1}_{\{M \leq x-y < M+u\}} f_{s-\tau}(x-y-u) f_{\tau}(y) \mu(du) dy$$

Kernel of (S_n, Y_{S_n}) given $Y_0 = x$

$$S_{x} = \sigma_{M-x} + \tau, \quad , Y_{S_{x}} = \begin{cases} 0 & Y_{S_{x}}^{-} > L - x \\ 0 & Y_{S_{x}}^{-} \le L - x, (1 - \rho) Y_{S_{x}}^{-} > M - x \\ x + (1 - \rho) Y_{S_{x}}^{-} & Y_{S_{x}}^{-} \le L - x, (1 - \rho) Y_{S_{x}}^{-} \le M - x \end{cases}$$

$$q_{x}(ds,du) = \mathbb{P}\left(S_{1} \in ds, Y_{S_{1}}^{-} \in du | Y_{0} = x\right)$$

$$\delta_{0}(du)\left(\int_{L-x}^{\infty} h^{M-x}(s,u) du + \mathbf{1}_{\{M-x < (1-\rho)(L-x)\}} \int_{\frac{M-x}{1-\rho}}^{L-x} h^{M-x}(s,u) du\right) ds$$

$$+ \mathbf{1}_{\{u > x\}} \mathbf{1}_{\{u-x < \min((L-x)(1-\rho), M-x)\}} h^{M-x}\left(s, \frac{u-x}{1-\rho}\right) \frac{du}{1-\rho} ds$$

 $\widehat{q}_{x}(s,u)$ kernel restricted to the operating states $Y_{0}=x$

$$\widehat{q}_{x}(s,u) = \delta_{0}(du) \int_{\frac{M-x}{1-\rho}}^{L-x} h^{M-x}(s,u) du + \mathbf{1}_{\left\{\frac{u-x}{1-\rho} < \min\left(L-x, \frac{M-x}{1-\rho}\right)\right\}} \frac{1}{1-\rho} h^{M-x}\left(s, \frac{u-x}{1-\rho}\right)$$

Transient Reliability for $t \leq \tau$

 $R_x(t)$ probability system is working in [0, t], $Y_0 = x \in [0, M]$:

$$R_x(t) = \mathbb{P}_x(T > t) = \mathbb{P}(\sigma_{L-x} > t) = \mathbb{P}(X_t < L - x) = F_t(L-x), \quad t < \tau$$

Transient Reliability for $t \geq \tau$

$$R_x(t) = \mathbb{P}_x(T > t, S_1 > t) + \mathbb{P}_x(T > t, S_1 \le t), \quad t \ge \tau$$

$$\begin{split} \mathbb{P}_{x}(T > t, S_{1} > t) &= \mathbb{P}(\sigma_{L-x} > t, \sigma_{M-x} + \tau > t) = G_{x}(t) \\ \mathbb{P}_{x}(T > t, S_{1} \le t) &= \mathbb{E} \Big[\mathbf{1}_{\{S_{x} \le t\}} \mathbf{1}_{\{Y_{S_{x}}^{-} < L-x\}} \mathbf{1}_{\{(1-\rho)Y_{S_{x}}^{-} \ge M-x\}} R_{0}(t-S_{x}) \Big] \\ &+ \mathbb{E} \Big[\mathbf{1}_{\{S_{x} \le t\}} \mathbf{1}_{\{Y_{S_{x}}^{-} < L-x\}} \mathbf{1}_{\{(1-\rho)Y_{S_{x}}^{-} < M-x\}} R_{x+(1-\rho)Y_{S_{x}}^{-}}(t-S_{x}) \Big] \end{split}$$

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Transient Reliability

For $t > \tau$ and $x \in [0, M]$, transient reliability fulfills

$$R_x(t) = G_x(t) + \int_{\tau}^t \int_0^M R_y(t-s)\widehat{q}_x(ds,dy)$$

where $\hat{q}_x(ds, dy)$ sub-semi-Markov kernel of (S_n, Y_{S_n}) given $Y_0 = x$ restricted to the operating states

$$G_{x}(t) = \mathbb{P}_{x}(T>t, S_{1}>t)$$

=
$$\int_{0}^{M-x} f_{t-\tau}(y) F_{\tau}(L-x-y) dy,$$

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Transient Availability for $t \leq \tau$

 $A_x(t)$ probability system is working at t given $Y_0 = x$ and t < au

$$A_x(t) = \mathbb{P}_x(Y_t < L) = \mathbb{P}(\sigma_{L-x} > t) = \mathbb{P}(X_t < L-x) = F_t(L-x), \quad t < \tau$$

Transient Availability for $t > \tau$

$$A_x(t) = \mathbb{P}_x(Y_t < L, S_1 > t) + \mathbb{P}_x(Y_t < L, S_1 \le t), \quad t \ge \tau$$

$$\begin{aligned} \mathbb{P}_{x}(Y_{t} < L, S_{1} > t) &= \mathbb{P}(\sigma_{L-x} > t, \sigma_{M-x} + \tau > t) \\ \mathbb{P}_{x}(T > t, S_{1} \le t) &= \mathbb{E}\Big[\mathbf{1}_{\{S_{x} \le t\}} \mathbf{1}_{\{Y_{S_{x}}^{-} \ge L-x\}} A_{0}(t-S_{x})\Big] \\ &+ \mathbb{E}\Big[\mathbf{1}_{\{S_{x} \le t\}} \mathbf{1}_{\{Y_{S_{x}}^{-} < L-x\}} \mathbf{1}_{\{(1-\rho)Y_{S_{x}}^{-} \ge M-x\}} A_{0}(t-S_{x})\Big] \\ &+ \mathbb{E}\Big[\mathbf{1}_{\{S_{x} \le t\}} \mathbf{1}_{\{Y_{S_{x}}^{-} < L-x\}} \mathbf{1}_{\{(1-\rho)Y_{S_{x}}^{-} < M-x\}} A_{x+(1-\rho)Y_{S_{x}}^{-}}(t-S_{x})\Big] \end{aligned}$$

Transient Availability

For $t > \tau$, availability fulfills

$$A_{x}(t)=G_{x}(t)+\int_{\tau}^{t}\int_{0}^{M}A_{y}(t-s)q_{x}(ds,dy),$$

with $G_x(t)$

$$G_{x}(t) = \mathbb{P}_{x}(Y_{t} > L, S_{1} > t)$$

=
$$\int_{0}^{M-x} f_{t-\tau}(y) F_{\tau}(L-x-y) dy,$$

Transient Expected Cost. First Maintenance Model

Transient cost

$$c_x(t)$$
 mean cost in $]0, t]$ given $Y_0 = x, x \in [0, M]$

 $c_x(t) = \mathbb{E}_x[C(]0,t])].$

 c_{CR} corrective replacement cost, c_{PR} preventive replacement cost, c_{PM} preventive repair cost and c_d downtime cost per unit time

Transient cost

For $t \leq \tau$

$$c_x(t) = c_d \int_0^t \mathbb{P}(t-u > \sigma_{L-x}) du = c_d \int_0^t \bar{F}_{t-u}(L-x) du$$

For $t > \tau$

$$c_{\mathsf{x}}(t) = \mathbb{E}_{\mathsf{x}}\left[C(]0,t]\mathbf{1}_{\{S_1 > t\}}\right] + \mathbb{E}_{\mathsf{x}}\left[C(]0,t]\mathbf{1}_{\{S_1 \le t\}}\right].$$

Transient Expected Cost. First Maintenance Model

Transient cost for $t > \tau$

The expected cost function at time $t > \tau$ with $Y_0 = x$ fulfills

$$c_x(t)=B_x(t)+\int_{\tau}^t\int_0^M c_y(t-s)q_x(ds,dy),$$

with $x \in [0, M]$, where

$$\begin{split} B_{X}(t) &= \mathbb{E}\Big[C(]0,t]\mathbf{1}_{\{S_{1}>t\}}\Big] + c_{d}\mathbb{E}_{x}\Big[(S_{1}-\sigma_{L})^{+}\mathbf{1}_{\{S_{1}\leq t\}}\Big] \\ &+ c_{CR}\mathbb{P}_{x}\Big(S_{1}\leq t,Y_{S_{1}^{-}}>L\Big) + (c_{PR+c_{PM}})\mathbb{E}_{x}\Bigg[\mathbf{1}_{\{S_{1}\leq t\}}\mathbf{1}_{\{Y_{S_{1}}^{-}\leq L\}}\mathbf{1}_{\{Y_{S_{1}}>M\}}\Bigg] \\ &+ c_{PM}\mathbb{E}_{x}\Bigg[\mathbf{1}_{\{S_{1}\leq t\}}\mathbf{1}_{\{Y_{S_{1}}^{-}\leq L\}}\mathbf{1}_{\{Y_{S_{1}}\leq L\}}\mathbf{1}_{\{Y_{S_{1}}\leq M\}}\Bigg] \end{split}$$

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Second Maintenance model

Description (Mercier and Castro, 2013)

- The system is working. It failed when degradation exceeds level L
- A signal is sent to the maintenance team when degradation reaches level M (0 < M < L) (at time σ_M).
- At $\sigma_M + \tau$, maintenance actions start
 - System is failed at maintenance time, corrective replacement
 - System is not failed at $\sigma_M + \tau(<\sigma_L)$, instantaneous imperfect repair that removes only some part (ρ %) of the age accumulated from the last maintenance time. After repair

- Degradation greater M, preventive replacement
- Degradation less M, goes on working

Second Maintenance Model



After S_n , evolution of $(Y_t)_{t>S_n}$ depends on $(Y_t)_{t\leq S_n}$ only through Y_{S_n} , (Y_t) semi-regenerative process with underlying MRP (S_n, Y_n) where $Y_n = Y_{S_n}$ and interarrival times $U'_n s$

Second Model. Markov Renewal Process

Kernel of the Markov Renewal Process $(S_n, Y_{S_n}, Y_{S_n^-})$

$$q_x(ds,du,dv) = \mathbb{P}\left(S_1 \in ds, Y_{S_1} \in du, Y_{S_1^-} \in dv | Y_0 = x\right), \quad x \in [0,M].$$

 $S_1 = \sigma_M + \tau$

$$(S_1, X_{(1-\rho)S_1}, X_{S_1}) \stackrel{\mathcal{L}}{=} (\sigma_M, X_{(1-\rho)\sigma_M}, X_{\sigma_M}) + (X_{\tau}, X_{(1-\rho)\tau}, X_{\tau}),$$

Calculating the p.d.f of $(\sigma_M, X_{(1-\rho)\sigma_M}, X_{\sigma_M})$ and p.d.f of $(\tau, X_{(1-\rho)\tau}, X_{\tau})$ (τ deterministic), by convolution we get the p.d.f $(S_1, X_{(1-\rho)S_1}, X_{S_1})$ and the kernel

Mistake

But
$$X_{(1-\rho)\tau} = X_{(1-\rho)(\sigma_M+\tau)} - X_{(1-\rho)\sigma_M}$$
 is not independent of σ_M

Second Model. Markov Renewal Process

Probability distribution function of $(S_1, X_{(1-\rho)S_1}, X_{S_1})$

Let φ be any measurable function, we compute

 $\mathbb{E}\left[\varphi(S_1, X_{(1-\rho)S_1}, X_{S_1})\right] = I_1(\varphi) + I_2(\varphi),$

$$\begin{split} h_1(\varphi) &= \mathbb{E}\Big[\varphi(S_1, X_{(1-\rho)S_1}, X_{S_1}) \mathbf{1}_{\{(1-\rho)(\sigma_M + \tau) > \sigma_M\}}\Big] \\ h_2(\varphi) &= \mathbb{E}\Big[\varphi(S_1, X_{(1-\rho)S_1}, X_{S_1}) \mathbf{1}_{\{(1-\rho)(\sigma_M + \tau) \le \sigma_M\}}\Big] \end{split}$$

we get

$$u^{M}(s,u,v) = f_{\rho s}(v-u) \int_{0}^{M} f_{s-\tau}(x) \left(\int_{M-x}^{\infty} f_{\tau-\rho s}(u-t-x)\mu(dt) \right) dx, \ \tau < s < \tau/\rho, \ M < u < v$$
$$u^{M}(s,u,v) = f_{(1-\rho)s}(u) \int_{M}^{\infty} f_{\tau}(v-w) \left(\int_{w-M}^{\infty} f_{\rho s-\tau}(w-u-t)\mu(dt) \right) dx, \ s > \tau/\rho, \ u < M < v$$

Second Model. Markov Renewal Process

Kernel of (S_n, Y_{S_n})

The kernel $(\bar{q}_x(ds, dy))$ of (S_n, Y_{S_n})

$$\bar{q}_{x}(ds,dy) = \nu_{x}(ds,dy) + \delta_{0}(dy) \int_{L-x}^{+\infty} \int_{0}^{z} u^{M-x}(s,w,z) dw dz$$

for $s > \tau$, $x \in [0, M]$ where

$$\nu_{x}(ds,dy) = \mathbf{1}_{\{y \leq M\}} \int_{M-x}^{L-x} u^{M-x}(s,y-x,v) \, dv \, dy \\ + \, \delta_{0}(dy) \int_{M-x}^{L-x} dz \int_{M-x}^{z} u^{M-x}(s,y,z) \, dy$$

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Reliability Measures. Second Maintenance Model

Transient Reliability

Transient reliability fulfills

$$R_{x}(t) = F_{t}(L-x), \quad t < \tau$$

$$R_{x}(t) = G_{x}(t) + \int_{\tau}^{t} \int_{0}^{M} R_{y}(t-s)\nu_{x}(ds,dy), \quad t > \tau$$

where ν_x (*ds*, *dy*) sub-semi-Markov kernel (S_n , Y_{S_n}) given $Y_0 = x$ restricted to the operating states

$$G_{x}(t) = \mathbb{P}_{x}(T>t, S_{1}>t)$$

=
$$\int_{0}^{M-x} f_{t-\tau}(y) F_{\tau}(L-x-y) dy,$$

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Reliability Measures. Second Maintenance Model

Transient Availability

Transient availability fulfills

$$\begin{array}{lll} A_x(t) &=& F_t(L-x), \quad t < \tau \\ A_x(t) &=& G_x(t) + \int_\tau^t \int_0^M A_y(t-s) \bar{q}_x(ds,dy), \quad t \geq \tau \end{array}$$

Transient expected cost

$$\begin{array}{lll} c_x(t) &=& c_d \int_0^\tau F_{t-u}(L-x) dx, \quad t < \tau \\ c_x(t) &=& B_x(t) + \int_\tau^t \int_0^M c_y(t-s) \bar{q}_x(ds,dy), \quad t \geq \tau \end{array}$$

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Data set

Gamma process parameters $\alpha = 1.5$, $\beta = 3$. Failure threshold L = 10, $\tau = 10$, $\rho = 0.5$, $C_c = 100$, $C_r = 5$, $C_p = 60$ and $C_u = 2$ (m.u.). MC simulation, 100 values from 0 to 10, and 40000 realizations in each point



Figure : Availability versus M at time t = 75



Figure : Expected cost versus M at time t = 75

Interpretation

Similar values availability, maximum difference of 19.1295 m.u for the expected cost rate. Model I: 7.69% repairs, 56.96% corrective replacements and 35.35% preventive replacements. Model II, 5.69% repairs, 56.93% corrective replacements and 35.43% preventive replacements

Data set

 $\alpha = 1.5$, $\beta = 3$. Failure threshold L = 10, $\tau = 10$, $\rho = 0.75$, $C_c = 100$, $C_r = 5$, $C_p = 60$ and $C_u = 2$ (m.u). MC simulation, 100 values from 0 to 10, and 40000 realizations in each point



Figure : Availability versus M at time t = 75



Figure : Expected cost versus M at time t = 75

Interpretation

Similar values availability, maximum difference of 10.14 m.u for the expected cost rate. Model I: 30.74% repairs, 55.34% corrective replacements and 13.91% preventive replacements. Model II, 30.68% repairs, 55.42% corrective replacements and 13.90% preventive replacements

Data set

 $\alpha=$ 1.5, $\beta=$ 3. Failure threshold L= 10, $\tau=$ 2, $\rho=$ 0.75, $C_c=$ 100, $C_r=$ 5, $C_\rho=$ 60 and $C_u=$ 2 (m.u)



Figure : Availability versus M at time t = 50

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Figure : Expected cost versus M at time t = 50

Interpretation

Similar values availability, maximum difference (Model I-Model II) of 255.7646 m.u for the expected cost rate but for low values of M = 0.20. Model I: 74.63% repairs, 4.64% corrective replacements and 20.73% preventive replacements. Model II, 69.94% repairs, 4.60% corrective replacements and 25.45% preventive replacements

Data set

 $\alpha = 1.5, \ \beta = 3$. Failure threshold $L = 10, \ \tau = 5, \ \rho = 0.75$



Figure : Reliability versus M at time t = 20

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Data set

 $\alpha=$ 1.5, $\beta=$ 3. Failure threshold L = 10, $\tau=$ 3, $\rho=$ 0.75



Figure : Reliability versus M at time t = 10

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Conclusions and further extensions

Conclusions

- Reliability analysis of a continuous degradation modelled as a gamma process with imperfect delay repair under two models considering the overshoot of the gamma process
- Fuctioning of the system is described through a semi-regenerative process
- Some transient reliability measures fulfill Markov renewal equations
- Numerical examples based on Monte-Carlo simulations are given. We get that transient and reliability are similar for the two models and the differences between them are found in the expected cost.

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Conclusions and further extensions

Further extension: Computing the recursive formulas

For transient measures, Markov renewal equation verifies

$$\begin{array}{lcl} M_{x}(t) & = & W_{x}(t), & t \leq \tau \\ M_{x}(t) & = & H_{x}(t) + \int_{\tau}^{t} \int_{0}^{M} M_{y}(t-s) Q_{x}(s,y) ds \, dy \quad t > \tau \end{array}$$

recursively for $t \leq \tau$

$$M_{x}(t) = M_{x}^{(1)}(t) = W_{x}(t), \quad t < \tau$$

for $(i-1)\tau < t < i\tau$

$$\begin{aligned} M_x(t) &= & M_x^{(i)}(t) \\ &= & H_x(t) + \sum_{k=1}^{i-1} \int_{t-(k+1)\tau}^{t-k\tau} \int_0^M M_y^{(k)}(t-\tau-w) Q_x(w+\tau,y) dw \, dy, \end{aligned}$$

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